CLAIMS

What is claimed is:

5   1.   A method of screening defects comprising
steps of:
       (a) measuring a quiescent current at a first supply
voltage for each of a plurality of devices;
       (b) measuring a quiescent current at a second supply
10   voltage for each of the plurality of devices;
       (c) generating a plot of the quiescent current
measured at the first supply voltage vs. the quiescent
current measured at the second supply voltage for each of
the plurality of devices;
15   (d) determining a range of intrinsic variation of
quiescent current in the plot; and
       (e) identifying any of the plurality of devices
corresponding to a measurement plotted outside the range
of intrinsic variation as defective.
20

       2.   The method of Claim 1 wherein the second
supply voltage has a value selected so that quiescent
current of substantially all of the plurality of devices
is within the range of intrinsic variation.
25

       3.   The method of Claim 1 wherein the first
supply voltage is a nominal supply voltage of the
plurality of devices.

4. The method of Claim 1 wherein the second supply voltage has a value selected in a sub-threshold voltage region of the plurality of devices.

5   5. The method of Claim 1 wherein the quiescent current is measured at the first supply voltage or the second supply voltage for multiple stop points in a test pattern.

10   6. The method of Claim 1 wherein the quiescent current is measured at the second supply voltage for only one stop point in a test pattern.

7. A computer program product for screening
15   defects comprising:
     a medium for embodying a computer program for input to a computer; and
     a computer program embodied in the medium for causing the computer to perform steps of:
20   (a) measuring a quiescent current at a first supply voltage for each of a plurality of devices;
     (b) measuring a quiescent current at a second supply voltage for each of the plurality of devices;
     (c) generating a plot of the quiescent current
25   measured at the first supply voltage vs. the quiescent current measured at the second supply voltage for each of the plurality of devices;
     (d) determining a range of intrinsic variation of quiescent current in the plot; and

(e) identifying any of the plurality of devices corresponding to a measurement plotted outside the range of intrinsic variation as defective.

5   8.   The computer program product of Claim 7 wherein the second supply voltage has a value selected so that quiescent current of substantially all of the plurality of devices is within the range of intrinsic variation.

10

9.   The computer program product of Claim 7 wherein the first supply voltage is a nominal supply voltage of the plurality of devices.

15   10.   The computer program product of Claim 7 wherein the second supply voltage has a value selected in a sub-threshold voltage region of the plurality of devices.

20   11.   The computer program product of Claim 7 wherein the quiescent current is measured at the first supply voltage or the second supply voltage for multiple stop points in a test pattern.

25   12.   The method of Claim 1 wherein the quiescent current is measured at the second supply voltage for only one stop point in a test pattern.